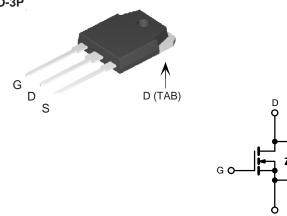


N-Channel 800V (D-S) Super Junction Power MOSFET

| PRODUCT SUMMARY | | | | | |
|--|-----------------|------|--|--|--|
| V _{DS} (V) at T _J max. | 850 | | | | |
| R _{DS(on)} typ. (Ω) at 25 °C | $V_{GS} = 10 V$ | 0.40 | | | |
| Q _g max. (nC) | 88 | | | | |
| Q _{gs} (nC) | 9 | | | | |
| Q _{gd} (nC) | 16 | | | | |
| Configuration | Single | | | | |





FEATURES

- Low figure-of-merit (FOM) Ron x Qg
- Low input capacitance (Ciss)
- · Reduced switching and conduction losses
- Ultra low gate charge (Q_g)
- Avalanche energy rated (UIS)



FREE

APPLICATIONS

- Server and telecom power supplies
- Switch mode power supplies (SMPS)
- Power factor correction power supplies (PFC)
- Lighting
 - High-intensity discharge (HID)
 - Fluorescent ballast lighting
- Industrial
 - Welding
 - Induction heating
 - Motor drives
 - Battery chargers
 - Renewable energy
 - Solar (PV inverters)

ABSOLUTE MAXIMUM RATINGS (T_C = 25 °C, unless otherwise noted) PARAMETER SYMBOL LIMIT UNIT Drain-source voltage V_{DS} 800 ٧ Gate-source voltage ± 30 V_{GS} T_C = 25 °C 11 Continuous drain current (T_J = 150 °C) V_{GS} at 10 V I_D $T_{\rm C} = 100 \,{}^{\circ}{\rm C}$ 8 А Pulsed drain current a 32 I_{DM} Linear derating factor 1.4 W/°C Single pulse avalanche energy b E_{AS} 226 mJ Maximum power dissipation P_D 179 W Operating junction and storage temperature range -55 to +150 °C T_J, T_{stq} T_{.1} = 125 °C 70 Drain-source voltage slope dV/dt V/ns Reverse diode dV/dt d 4.3 Soldering recommendations (peak temperature) ^c For 10 s 300 °C

N-Channel MOSFET

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature

b. V_{DD} = 140 V, starting T_J = 25 °C, L = 28.2 mH, R_g = 25 $\Omega,$ I_{AS} = 4.0 A

c. 1.6 mm from case

d. $I_{SD} \leq I_D, \, dl/dt$ = 100 A/µs, starting T_J = 25 $^\circ C$



| THERMAL RESISTANCE RATINGS | | | | | | | |
|----------------------------------|-------------------|------|------|------|--|--|--|
| PARAMETER | SYMBOL | TYP. | MAX. | UNIT | | | |
| Maximum junction-to-ambient | R _{thJA} | - | 62 | °C/W | | | |
| Maximum junction-to-case (drain) | R _{thJC} | - | 0.7 | C/W | | | |

| PARAMETER | SYMBOL | TES | TEST CONDITIONS | | TYP. | MAX. | UNIT |
|---|-----------------------|---|---|-----|------|-------|------|
| Static | | | | • | • | • | |
| Drain-source breakdown voltage | V _{DS} | $V_{GS} = 0 V, I_D = 250 \mu A$ | | 800 | - | - | V |
| V _{DS} temperature coefficient | $\Delta V_{DS}/T_{J}$ | Reference to 25 °C, I _D = 1 mA | | - | 1.1 | - | V/°C |
| Gate-source threshold voltage (N) | V _{GS(th)} | $V_{DS} = V_{GS}, I_{D} = 250 \ \mu A$ | | 2 | - | 4 | V |
| Gate-source leakage | I _{GSS} | $V_{GS} = \pm 20 V$ | | - | - | ± 100 | nA |
| | | , v | $V_{GS} = \pm 30 \text{ V}$ | | - | ± 1 | μA |
| Zero gate voltage drain current | I _{DSS} | V _{DS} = | V _{DS} = 800 V, V _{GS} = 0 V | | - | 1 | |
| | | V _{DS} = 640 V | V _{DS} = 640 V, V _{GS} = 0 V, T _J = 125 °C | | - | 10 | μA |
| Drain-source on-state resistance | R _{DS(on)} | $V_{GS} = 10 V$ | I _D = 5.5 A | - | 0.40 | - | Ω |
| Forward transconductance | 9 _{fs} | V _{DS} = 30 V, I _D = 5.5 A | | - | 4.5 | - | S |
| Dynamic | | | | | | | |
| Input capacitance | C _{iss} | | $V_{GS} = 0 V$, | | 1670 | - | pF |
| Output capacitance | C _{oss} | $V_{DS} = 100 V,$ f = 1 MHz | | - | 68 | - | |
| Reverse transfer capacitance | C _{rss} | | | - | 9 | - | |
| Effective output capacitance, energy related ^a | C _{o(er)} | $V_{\rm DS}$ = 0 V to 480 V, $V_{\rm GS}$ = 0 V | | - | 43 | - | |
| Effective output capacitance, time related ^b | C _{o(tr)} | | | - | 212 | - | |
| Total gate charge | Qg | | | - | 44 | 88 | |
| Gate-source charge | Q _{gs} | $V_{GS} = 10 V$ | $V_{GS} = 10 \text{ V}$ $I_D = 5.5 \text{ A}, V_{DS} = 480 \text{ V}$ | | 9 | - | nC |
| Gate-drain charge | Q _{gd} | | | | 16 | - | |
| Turn-on delay time | t _{d(on)} | V_{DD} = 480 V, I _D = 5.5 A, V _{GS} = 10 V, R _g = 9.1 Ω | | - | 18 | 36 | - ns |
| Rise time | t _r | | | - | 15 | 30 | |
| Turn-off delay time | t _{d(off)} | | | - | 55 | 110 | |
| Fall time | t _f | | | - | 18 | 36 | |
| Gate input resistance | Rg | f = 1 MHz, open drain | | 0.4 | 0.9 | 1.8 | Ω |
| Drain-Source Body Diode Characteristic | s | | | | | • | |
| Continuous source-drain diode current | ۱ _S | MOSFET symbol showing the integral reverse p - n junction diode | | - | - | 12 | A |
| Pulsed diode forward current | I _{SM} | | | - | - | 32 | |
| Diode forward voltage | V _{SD} | T _J = 25 °C, I _S = 5.5 A, V _{GS} = 0 V | | - | - | 1.2 | V |
| Reverse recovery time | t _{rr} | T _J = 25 °C, $I_F = I_S = 5.5 \text{ A}$, di/dt = 100 A/ μ s, $V_R = 25 \text{ V}$ | | - | 345 | 690 | ns |
| Reverse recovery charge | Q _{rr} | | | - | 4.2 | 8.4 | μC |
| Reverse recovery current | I _{RRM} | | | - | 21 | - | A |

Notes

a. $C_{oss(er)}$ is a fixed capacitance that gives the same energy as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} b. $C_{oss(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS}



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

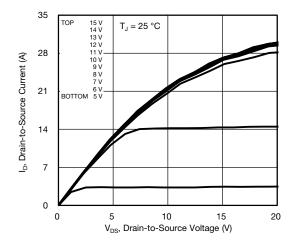


Fig. 1 - Typical Output Characteristics

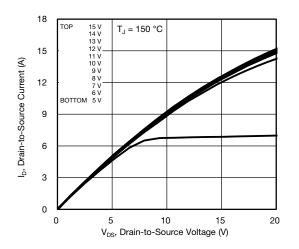


Fig. 2 - Typical Output Characteristics

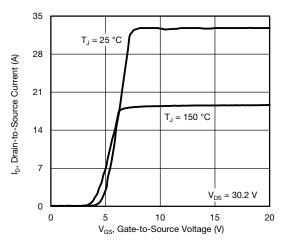


Fig. 3 - Typical Transfer Characteristics

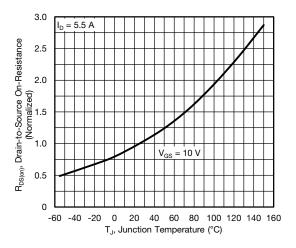


Fig. 4 - Normalized On-Resistance vs. Temperature

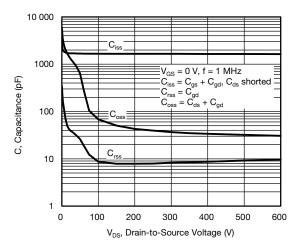


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

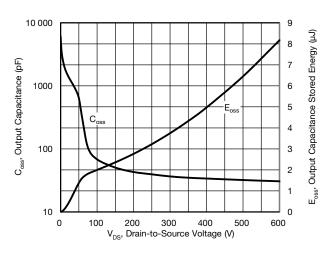


Fig. 6 - C_{oss} and E_{oss} vs. V_{DS}

VBPB18R11S



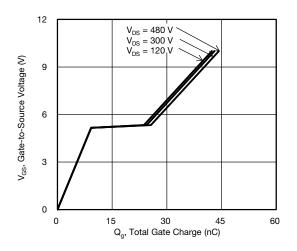


Fig. 7 - Typical Gate Charge vs. Gate-to-Source Voltage

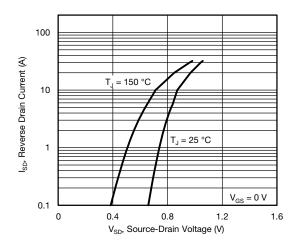


Fig. 8 - Typical Source-Drain Diode Forward Voltage

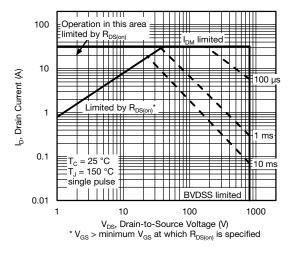


Fig. 9 - Maximum Safe Operating Area

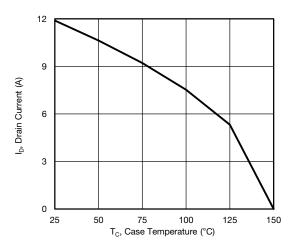


Fig. 10 - Maximum Drain Current vs. Case Temperature

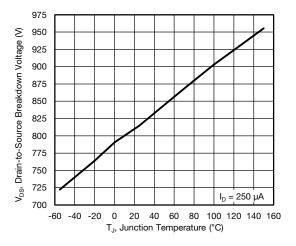


Fig. 11 - Temperature vs. Drain-to-Source Voltage

VBPB18R11S

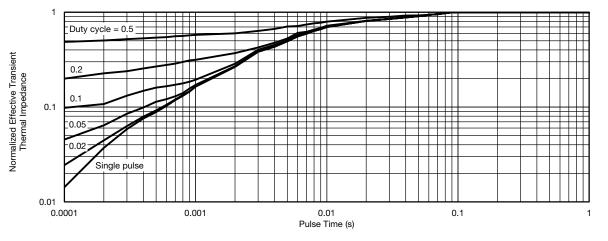


Fig. 12 - Normalized Thermal Transient Impedance, Junction-to-Case

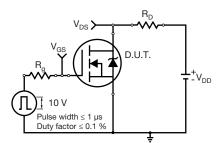


Fig. 13 - Switching Time Test Circuit

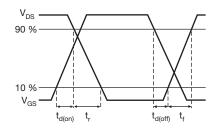


Fig. 14 - Switching Time Waveforms

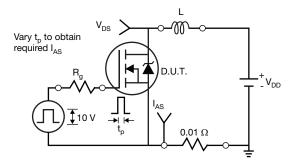


Fig. 15 - Unclamped Inductive Test Circuit

Fig. 16 - Unclamped Inductive Waveforms

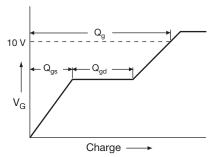


Fig. 17 - Basic Gate Charge Waveform

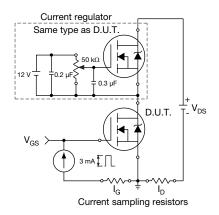


Fig. 18 - Gate Charge Test Circuit

semi

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Peak Diode Recovery dV/dt Test Circuit

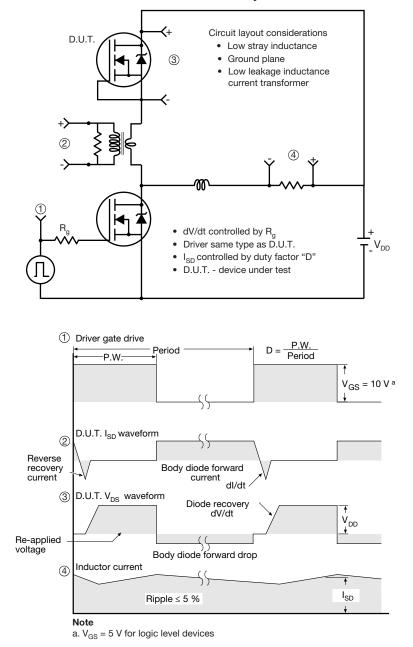
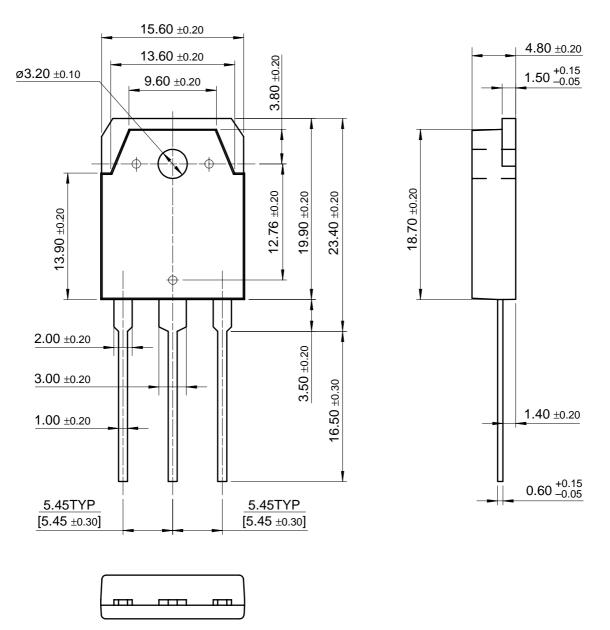


Fig. 19 - For N-Channel



TO-3P





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